

600V 3-Phase Bridge Driver

PRODUCT SUMMARY

- V_{OFFSET} 600 V max.
- $I_{\text{O}+/-}$ 250 mA / 350 mA
- V_{OUT} 10 V - 20 V
- $t_{\text{on/off}}$ (typ.) 400 ns / 380 ns
- **Deadtime (typ.)** 290 ns

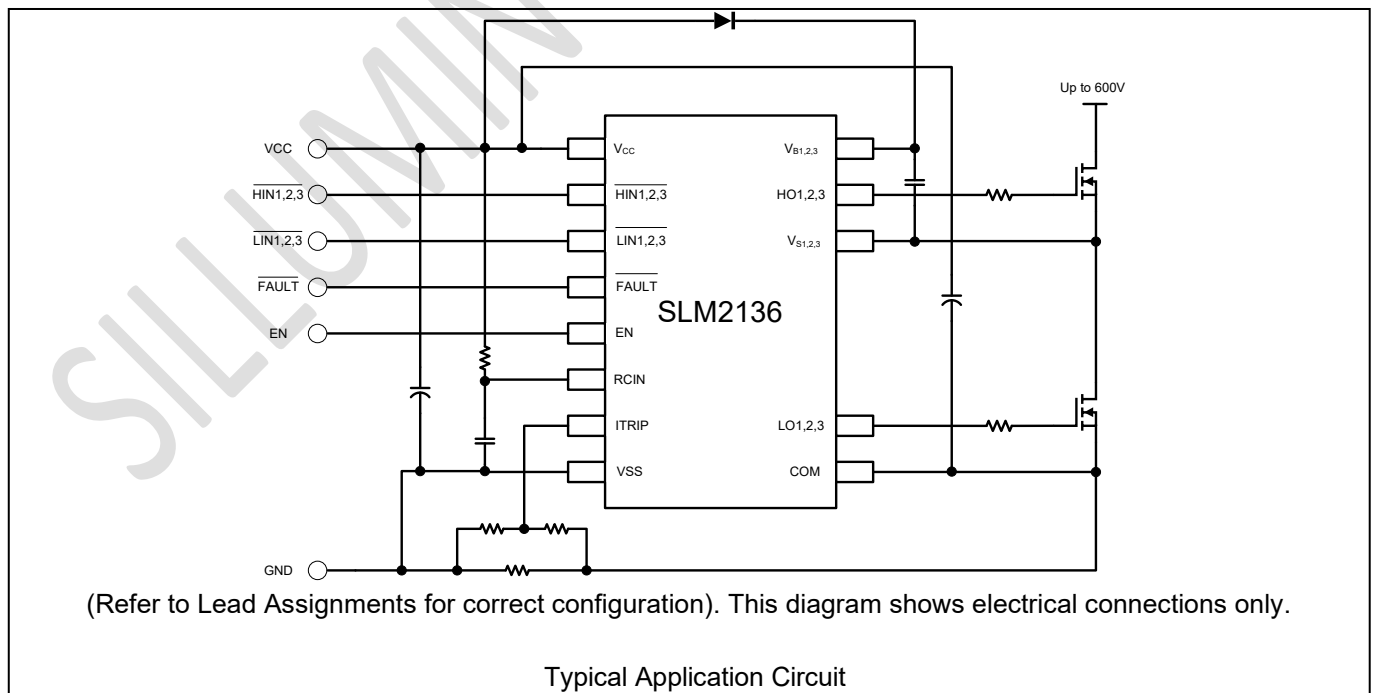
FEATURES

- Floating channel designed for bootstrap operation
- Fully operational to +600 V
- Tolerant to negative transient voltage, dV/dt immune
- Gate drive supply range from 10 V to 20 V
- Undervoltage lockout for all channels
- Low/high side output out of phase with inputs
- 3.3 V, 5 V, and 15 V logic compatible
- Lower di/dt gate drive for better noise immunity
- Cross-conduction prevention logic
- Matched propagation delay for both channels
- Externally programmable delay for automatic fault clear
- SOIC-28L package

GENERAL DESCRIPTION

The SLM2136 is a high voltage, high speed power MOSFET and IGBT drivers with three independent high- and low-side referenced output channels for 3-phase applications. Proprietary HVIC and latch immune CMOS technologies enable ruggedized monolithic construction. The logic inputs are compatible with standard CMOS or LSTTL output, down to 3.3 V logic. A current trip function which terminates all six outputs can be derived from an external current sense resistor. An enable function is available to terminate all six outputs simultaneously. An open-drain FAULT signal is provided to indicate that an overcurrent or undervoltage shutdown has occurred. Overcurrent fault conditions are cleared automatically after a delay programmed externally via an RC network connected to the RCIN input. The output drivers feature a high pulse current buffer stage designed for minimum driver cross conduction. Propagation delays are matched to simplify use in high frequency applications. The floating channel can be used to drive an N-channel power MOSFET or IGBT in the high-side configuration which operates up to 600 V.

TYPICAL APPLICATION CIRCUIT



PIN CONFIGURATION

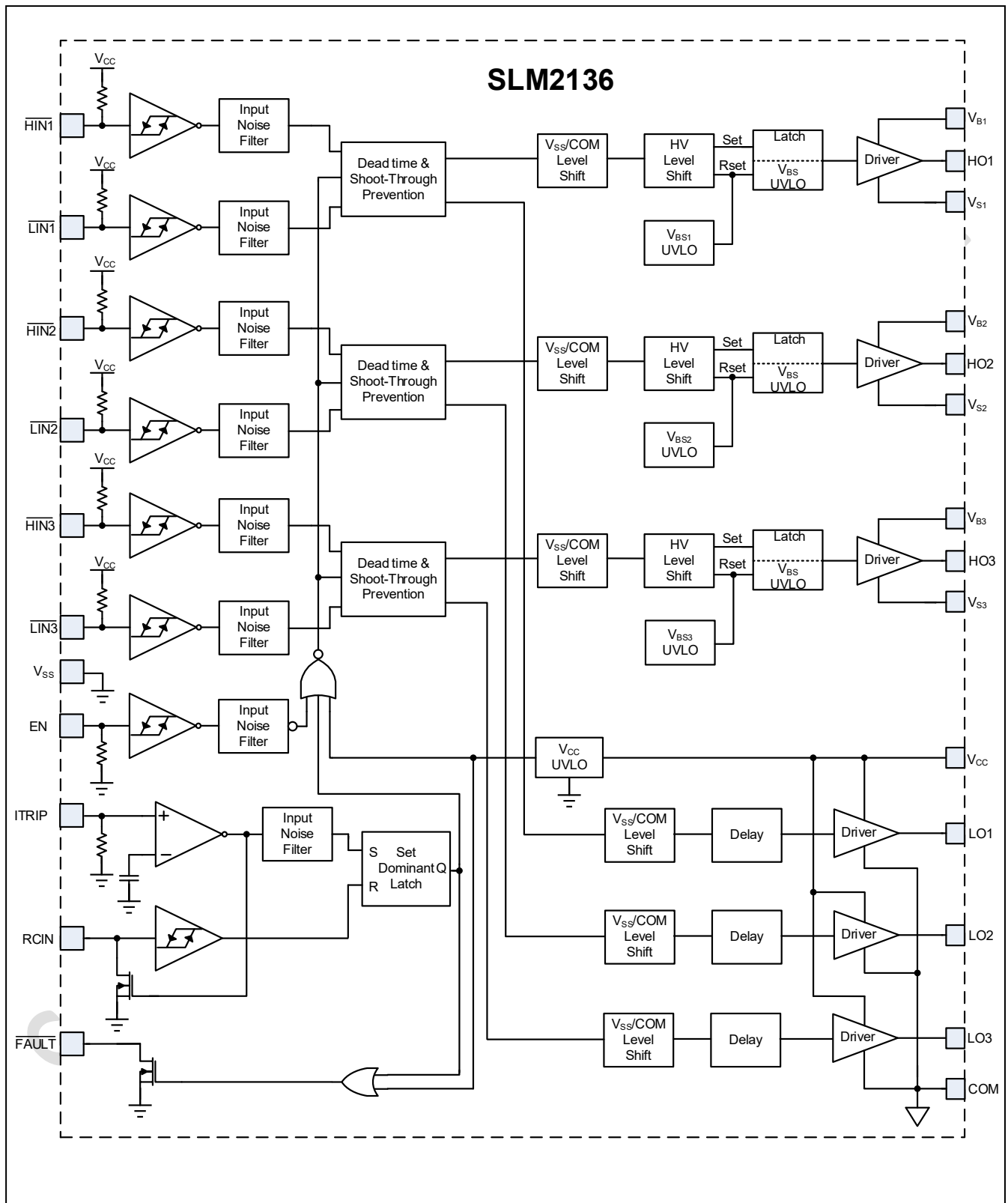
Package	Pin Configuration (Top View)			
SOIC-28L	1	V _{CC}	V _{B1}	28
	2	HIN1	HO1	27
	3	HIN2	V _{S1}	26
	4	HIN3		25
	5	LIN1	V _{B2}	24
	6	LIN2	HO2	23
	7	LIN3	V _{S2}	22
	8	FAULT		21
	9	ITRIP	V _{B3}	20
	10	EN	HO3	19
	11	RCIN	V _{S3}	18
	12	V _{SS}		17
	13	COM	LO1	16
	14	LO3	LO2	15

PIN DESCRIPTION

No.	Pin	Description
1	V _{CC}	Low-side and logic fixed supply.
2, 3, 4	HIN1, 2, 3	Logic input for high-side gate driver output (HO), out of phase.
5, 6, 7	LIN1, 2, 3	Logic input for low-side gate driver output (LO), out of phase.
8	FAULT	Indicates over-current (ITRIP) or low-side undervoltage lockout has occurred. Negative logic, open-drain output.
9	ITRIP	Analog input for overcurrent shutdown. When active, ITRIP shuts down outputs and activates FAULT and RCIN low. When ITRIP becomes inactive, FAULT stays active low for an externally set time T _{FLTCLR} , then automatically becomes inactive (open-drain high impedance).
10	EN	Logic input to enable I/O functionality. I/O logic functions when ENABLE is high. No effect on FAULT and not latched.
11	RCIN	External RC network input used to define FAULT CLEAR delay, T _{FLTCLR} , approximately equal to R*C. When RCIN>8 V, the FAULT pin goes back into open-drain high-impedance.
12	V _{SS}	Logic ground.
13	COM	Low-side gate drivers return.
14, 15, 16	LO1, 2, 3	Low-side gate driver outputs.
18, 22, 26	V _{S1, 2, 3}	High-side floating supply return.
19, 23, 27	HO1, 2, 3	High-side gate driver outputs.
20, 24, 28	V _{B1, 2, 3}	High-side floating supply.

ORDERING INFORMATION
Industrial Range: -40°C to +125°C

Order Part No.	Package	QTY
SLM2136CF-DG	SOIC-28L, Pb-Free	1000/Reel

FUNCTIONAL BLOCK DIAGRAM


ABSOLUTE MAXIMUM RATINGS

Symbol	Definition		Min.	Max.	Units
V_B	High-side floating absolute voltage		-0.3	625	V
V_S	High-side floating supply offset voltage		$V_{B1,2,3} - 25$	$V_{B1,2,3} + 0.3$	
V_{HO}	High-side floating output voltage		$V_{S1,2,3} - 0.3$	$V_{B1,2,3} + 0.3$	
V_{CC}	Low-side and logic fixed supply voltage		-0.3	25	
V_{SS}	Logic ground		$V_{CC} - 25$	$V_{CC} + 0.3$	
V_{IN}	Logic input voltage (LIN, HIN, ITRIP, EN)		$V_{SS} - 0.3$	Lower of ($V_{SS} + 15$) or ($V_{CC} + 0.3$)	
$V_{LO1,2,3}$	Low-side output voltage		-0.3	$V_{CC} + 0.3$	
V_{RCIN}	RCIN input voltage		$V_{SS} - 0.3$	$V_{CC} + 0.3$	
V_{FLT}	FAULT onput voltage		$V_{SS} - 0.3$	$V_{CC} + 0.3$	
dV_S/dt	Allowable offset supply voltage transient		---	50	V/ns
P_D	Package power dissipation @ $T_A \leq +25^\circ\text{C}$	SOIC-28L	---	1.6	W
R_{thJA}	Thermal resistance, junction to ambient	SOIC-28L	---	75	$^\circ\text{C}/\text{W}$
T_J	Junction temperature		---	150	$^\circ\text{C}$
T_S	Storage temperature		-55	150	
T_L	Lead temperature (soldering, 10 seconds)		---	300	

Note:

Absolute maximum ratings indicate sustained limits beyond which damage to the device may occur. All voltage parameters are absolute voltages referenced to COM. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions.

RECOMMENDED OPERATING CONDITIONS

Symbol	Definition		Min.	Max.	Units
$V_{B1,2,3}$	High-side floating supply voltage		$V_{S1,2,3} + 10$	$V_{S1,2,3} + 20$	V
$V_{S1,2,3}$	High-side floating supply offset voltage		Note 1	600	
$V_{HO1,2,3}$	High-side floating output voltage		$V_{S1,2,3}$	$V_{B1,2,3}$	
$V_{LO1,2,3}$	Low-side output voltage		0	V_{CC}	
V_{CC}	Low-side and logic fixed supply voltage		10	20	
V_{SS}	Logic ground		-5	5	
V_{FLT}	FAULT output voltage		V_{SS}	V_{CC}	
V_{RCIN}	RCIN input voltage		V_{SS}	V_{CC}	
V_{ITRIP}	ITRIP input voltage		V_{SS}	$V_{SS} + 5V$	
V_{IN}	Logic input voltage LIN1, 2, 3, HIN1, 2, 3		V_{SS}	$V_{SS} + 5V$	$^\circ\text{C}$
T_A	Ambient temperature		- 40	125	

Note:

- Logic operational for V_S of (COM – 5 V) to (COM + 600V). Logic state held for V_S of (COM-5V) to (COM - V_{BS}).
- All input pins and the ITRIP and EN pins are internally clamped with a 5.2V zener diode.
- The input/output logic timing diagram is shown in Fig. 1.
- For proper operation the device should be used within the recommended conditions.
- The V_S offset rating is tested with all supplies biased at a 15 V differential.

DYNAMIC ELECTRICAL CHARACTERISTICS
 $V_{BIAS} (V_{CC}, V_{BS}) = 15\text{ V}$, $V_{S1,2,3} = V_{SS} = \text{COM}$, $C_L = 1000\text{ pF}$ and $T_A = 25^\circ\text{C}$ unless otherwise specified.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Unit
t_{on}	Turn-on propagation delay	$V_S = 0\text{ V}$	300	425	550	ns
t_{off}	Turn-off propagation delay	$V_S = 600\text{ V}$	250	400	550	
t_r	Turn-on rise time		---	125	190	
t_f	Turn-off fall time		---	50	75	
t_{EN}	Enable low to output shutdown propagation delay	$V_{IN}, V_{EN} = 0\text{ V or } 5\text{ V}$	300	450	600	
t_{ITRIP}	ITRIP to output shutdown propagation delay	$V_{ITRIP} = 5\text{ V}$	500	750	1000	
t_{bl}	ITRIP blanking time	$V_{IN} = 0\text{ V or } 5\text{ V}$ $V_{ITRIP} = 5\text{ V}$	100	150	---	
t_{FLT}	ITRIP to $\overline{\text{FAULT}}$ propagation delay	$V_{IN} = 0\text{ V or } 5\text{ V}$ $V_{ITRIP} = 5\text{ V}$	400	600	800	
t_{FILIN}	Input filter time (HIN, LIN)	$V_{IN} = 0\text{ V \& } 5\text{ V}$	100	200	---	
t_{FLTCLR}	FAULT clear time RCIN: $R = 2\text{ M}\Omega$, $C = 1\text{ nF}$	$V_{IN} = 0\text{ V or } 5\text{ V}$ $V_{ITRIP} = 0\text{ V}$	1.3	1.65	2	ms
DT	Deadtime, LS turn-off to HS turn-on & HS turn-on to LS turn-off	$V_{IN} = 0\text{ V \& } 5\text{ V}$	220	290	360	ns
MT	Matching delay, HS & LS turn-on/off	External dead time > 400 ns	---	40	75	
MDT	Matching delay, max (t_{on}, t_{off}) – min (t_{on}, t_{off}), (t_{on}, t_{off} are applicable to all 3 channels)		---	25	70	
PM	Output pulse width matching (pwin - pwout) (Fig. 2)		---	40	75	

STATIC ELECTRICAL CHARACTERISTICS
 $V_{BIAS} (V_{CC}, V_{BS1,2,3}) = 15\text{ V}$ and $T_A = 25^\circ\text{C}$ unless otherwise specified. The V_{IN} , V_{TH} , and I_{IN} parameters are referenced to V_{SS} and are applicable to all 6 channels ($\overline{\text{LIN1, 2, 3}}$ and $\overline{\text{HIN1, 2, 3}}$). The V_O and I_O parameters are referenced to COM and $V_{S1,2,3}$ and are applicable to the respective output leads: HO1,2,3 and LO1,2,3.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Unit
V_{IH}	Logic "0" input voltage ($\overline{\text{LIN1, 2, 3}}$ and $\overline{\text{HIN1, 2, 3}}$)	$V_{CC} = 10\text{ V to } 20\text{ V}$	2.0	---	---	V
V_{IL}	Logic "1" input voltage ($\overline{\text{LIN1, 2, 3}}$ and $\overline{\text{HIN1, 2, 3}}$)		---	---	1.0	
$V_{EN, TH+}$	Enable positive going threshold		---	---	1.7	
$V_{EN, TH-}$	Enable negative going threshold		1.0	---	---	
$V_{IT, TH+}$	ITRIP positive going threshold		0.4	0.5	0.6	

$V_{IT, HYS}$	ITRIP input hysteresis		---	0.1	---	V
$V_{RCIN, TH+}$	RCIN positive going threshold		---	8	---	
$V_{RCIN, HYS}$	RCIN input hysteresis		---	1	---	
V_{OH}	High level output voltage, $V_{BIAS} - V_O$	$I_O = 20\text{ mA}$	---	0.5	1.0	
V_{OL}	Low level output voltage, V_O		---	0.3	0.6	
V_{CCUV+} V_{BSUV+}	V_{CC} and V_{BS} supply undervoltage positive going threshold		8.0	8.9	9.8	
V_{CCUV-} V_{BSUV-}	V_{CC} and V_{BS} supply undervoltage negative going threshold		7.4	8.2	9.0	
V_{CCUVH} V_{BSUVH}	V_{CC} and V_{BS} supply undervoltage lockout hysteresis		0.3	0.7	---	
V_{IN_CLAMP}	Input clamp voltage (HIN, LIN, ITRIP and EN)	$I_{IN} = 100\text{ }\mu\text{A}$	---	5.8	---	μA
I_{LK}	Offset supply leakage current	$V_{B1,2,3} = V_{S1,2,3} = 600\text{ V}$	---	---	50	
I_{QBS}	Quiescent V_{BS} supply current	$V_{IN} = 0\text{ V or } 5\text{ V}$	---	60	75	
I_{QCC}	Quiescent V_{CC} supply current		---	1.6	2.3	mA
I_{IN+}	Logic “1” input bias current	$\overline{HIN1, 2, 3} = 0\text{ V},$ $\overline{LIN1, 2, 3} = 0\text{ V}$	---	150	200	μA
I_{IN-}	Logic “0” input bias current	$\overline{HIN1, 2, 3} = 5\text{ V},$ $\overline{LIN1, 2, 3} = 5\text{ V}$	---	200	300	
I_{ITRIP+}	“High” ITRIP input bias current	$V_{ITRIP} = 5\text{ V}$	---	30	100	
I_{ITRIP-}	“Low” ITRIP input bias current	$V_{ITRIP} = 0\text{ V}$	---	0	1	
I_{EN+}	“High” ENABLE input bias current	$V_{ENABLE} = 5\text{ V}$	---	35	100	
I_{EN-}	“Low” ENABLE input bias current	$V_{ENABLE} = 0\text{ V}$	---	0	1	
I_{RCIN}	RCIN input bias current	$V_{RCIN} = 0\text{ V or } 15\text{ V}$	---	0	1	
I_{O+}	Output high short circuit pulsed current	$V_O = 0\text{ V}, V_{IN} = V_{IH}$ $PW \leq 10\text{ }\mu\text{s}$	120	200	---	mA
I_{O-}	Output low short circuit pulsed current	$V_O = 15\text{ V}, V_{IN} = V_{IL}$ $PW \leq 10\text{ }\mu\text{s}$	250	350	---	
R_{on_RCIN}	RCIN low on resistance		---	50	100	Ω
R_{on_FAULT}	FAULT low on resistance		---	50	100	

VCC	VBS	ITRIP	ENABLE	FAULT	LO1,2,3	HO1,2,3
< UVCC	X	X	X	0 (note 1)	0	0
15 V	< UVBS	0 V	5 V	High imp	LIN1,2,3	0
15 V	15 V	0 V	5 V	High imp	LIN1,2,3	HIN1,2,3
15 V	15 V	> V _{ITRIP}	5 V	0 (note 2)	0	0
15 V	15 V	0 V	0 V	High imp	0	0

Note:

1. A shoot-through prevention logic prevents LO1,2,3 and HO1,2,3 for each channel from turning on simultaneously.
2. UVCC is not latched, when V_{CC} > UV_{CC}, FAULT returns to high impedance.
3. When ITRIP < V_{ITRIP}, FAULT returns to high-impedance after RCIN pin becomes greater than 8 V (@ V_{CC} = 15 V).

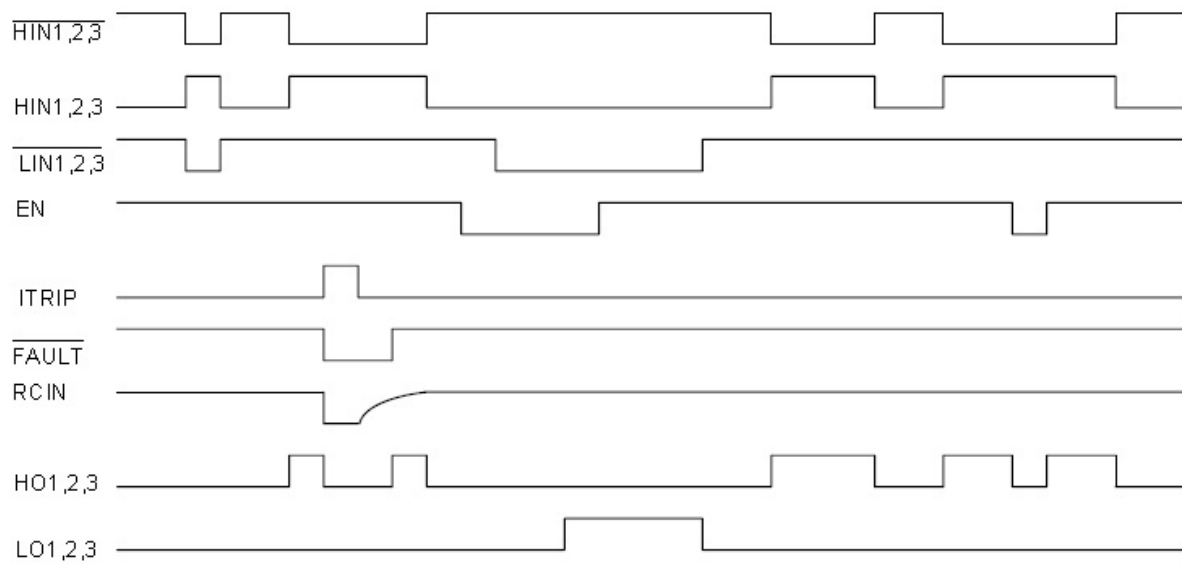


Fig. 1. Input/Output Timing Diagram

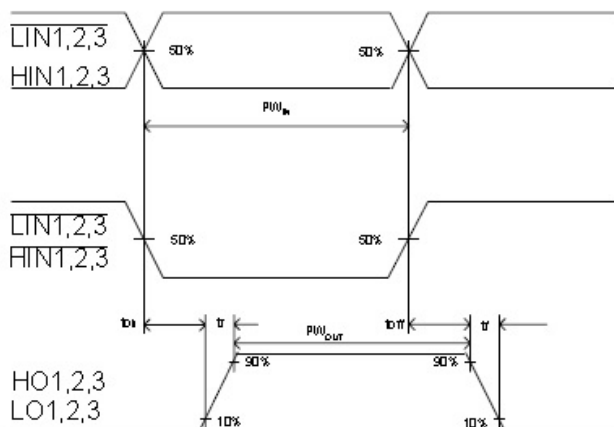


Fig. 2. Switching Time Waveforms

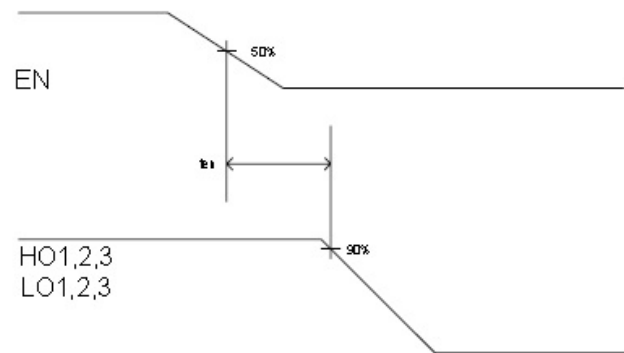


Fig. 3. Output Enable Timing Waveform

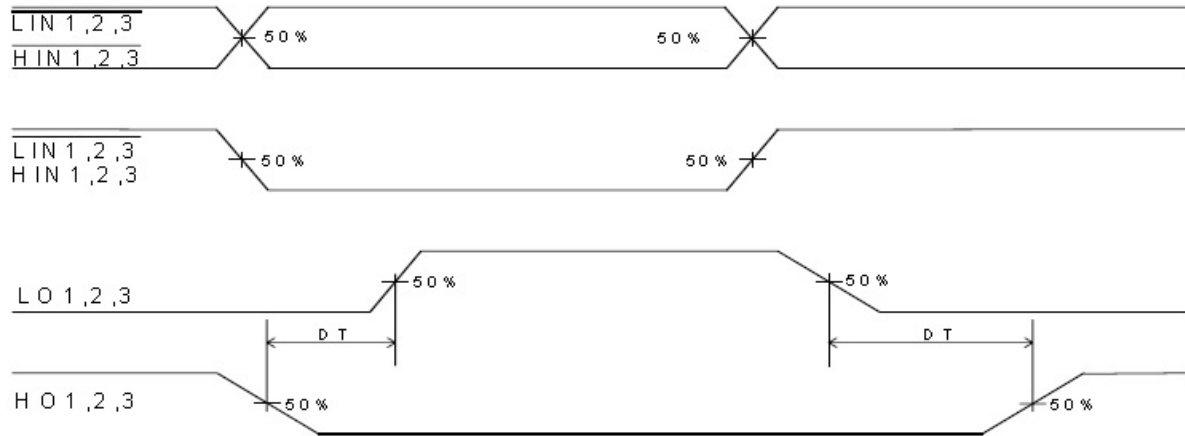


Fig. 4. Internal Deadtime Timing Waveforms

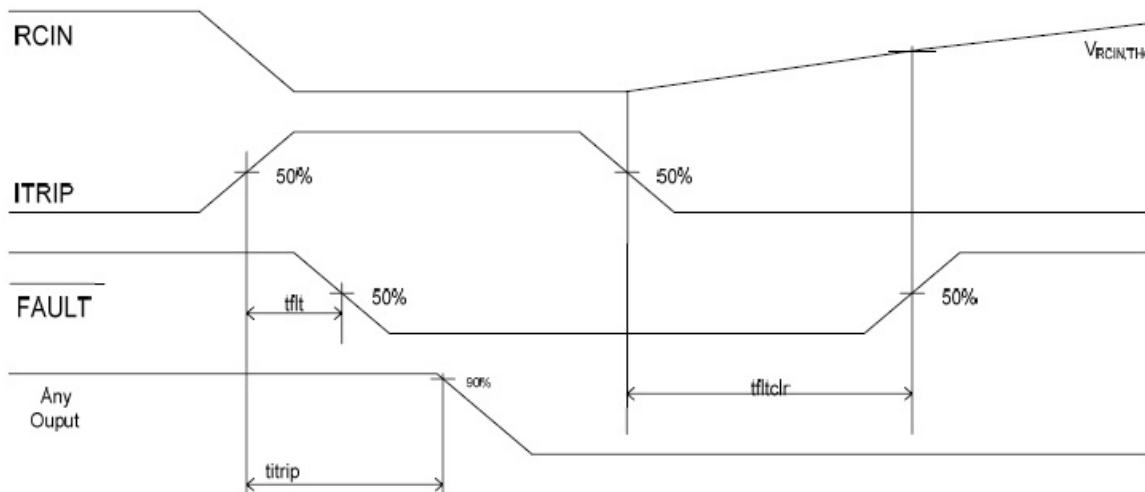


Fig. 5. ITRIP/RCIN Timing Waveforms

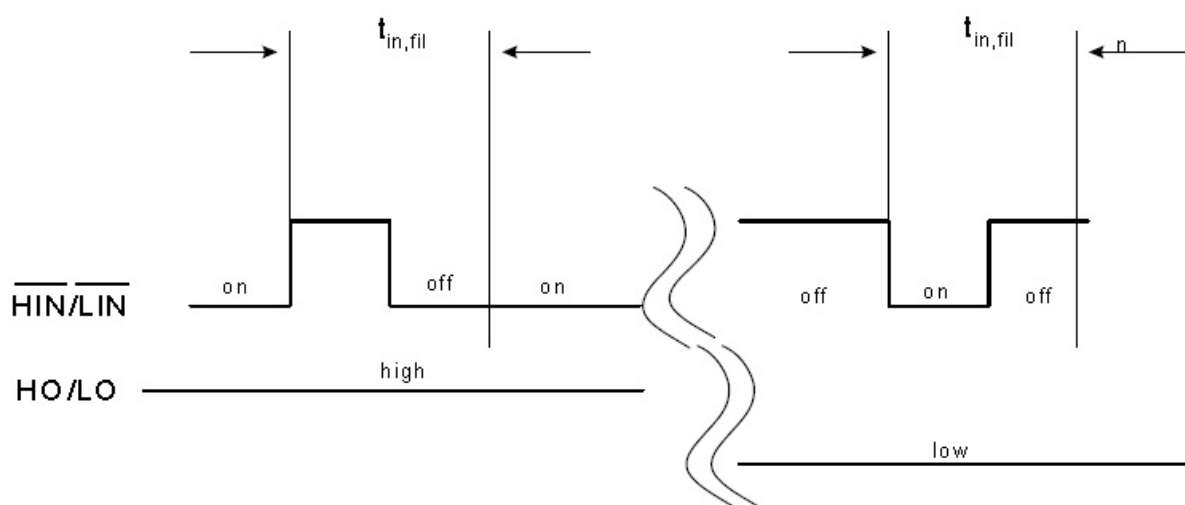


Fig. 6. Input Filter Function

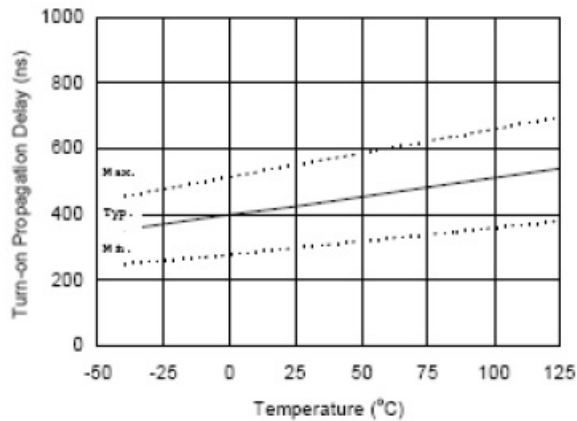


Figure 6A. Turn-on Propagation Delay vs. Temperature

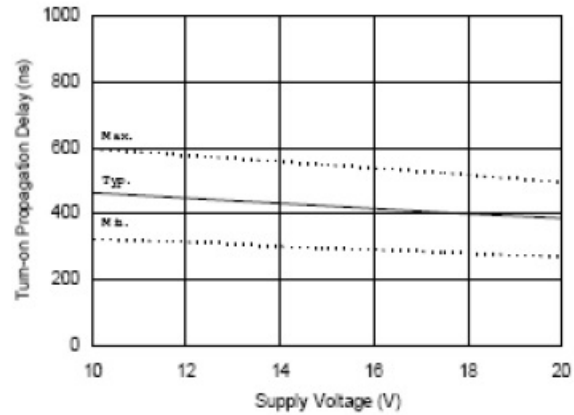


Figure 6B. Turn-on Propagation Delay vs. Supply Voltage

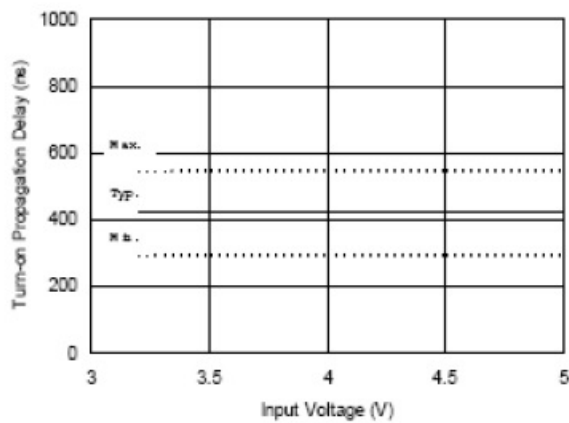


Figure 6C. Turn-on Propagation Delay vs. Input Voltage

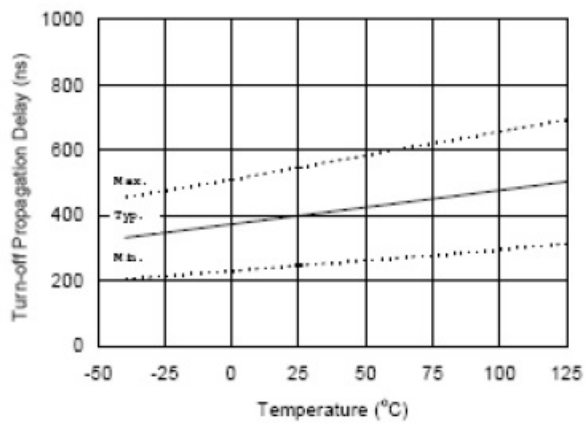


Figure 7A. Turn-off Propagation Delay vs. Temperature

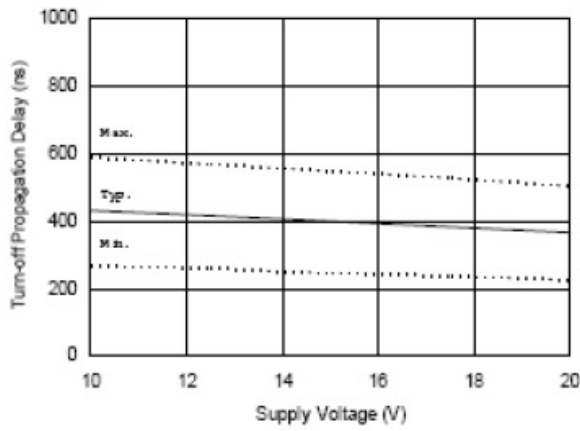


Figure 7B. Turn-off Propagation Delay vs. Supply Voltage

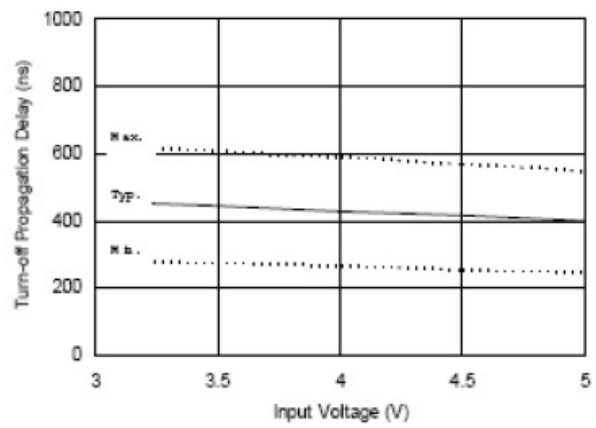


Figure 7C. Turn-off Propagation Delay vs. Input Voltage

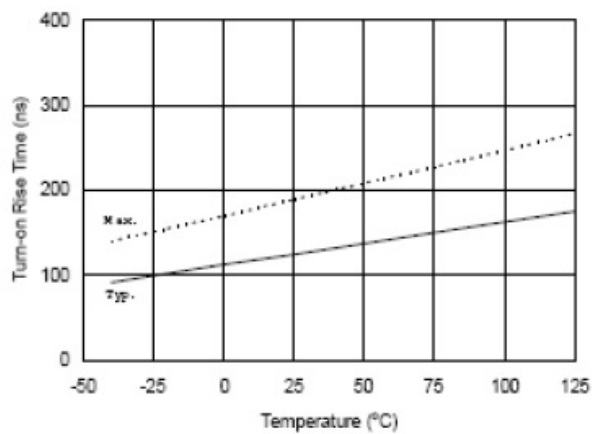


Figure 8A. Turn-on Rise Time vs. Temperature

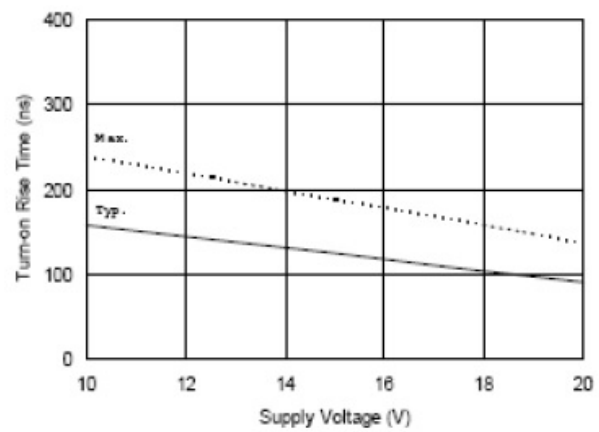


Figure 8B. Turn-on Rise Time vs. Supply Voltage

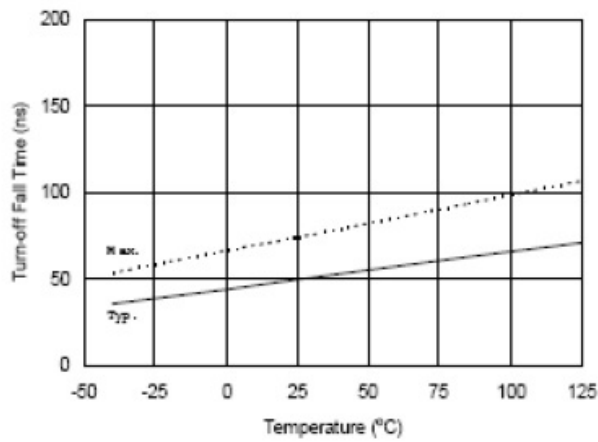


Figure 9A. Turn-off Fall Time vs. Temperature

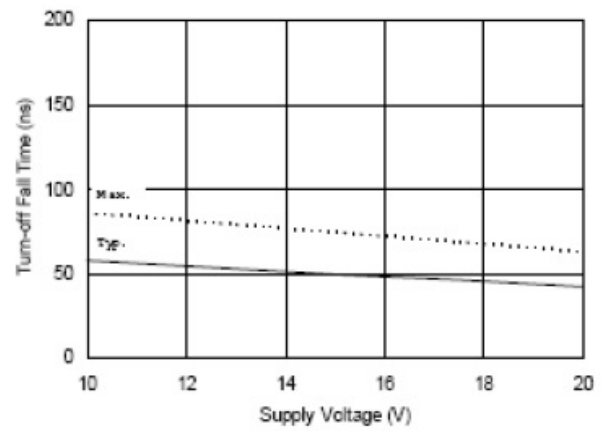


Figure 9B. Turn-off Fall Time vs. Supply Voltage

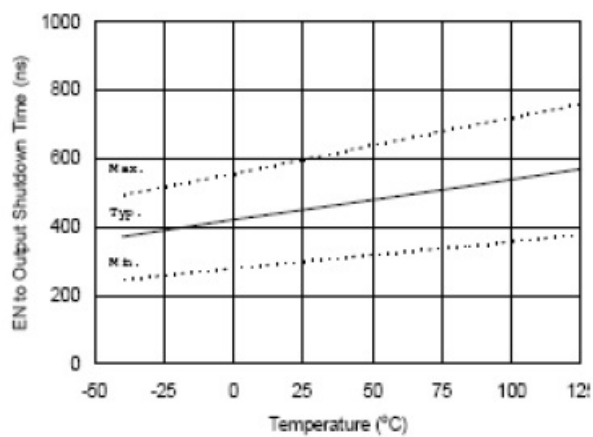


Figure 10A. EN to Output Shutdown Time vs. Temperature

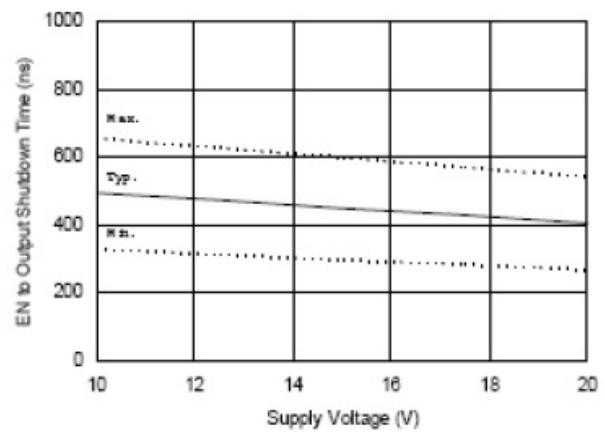


Figure 10B. EN to Output Shutdown Time vs. Supply Voltage

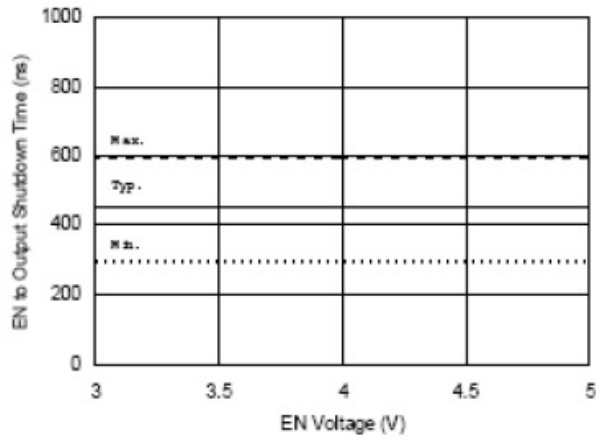


Figure 10C. EN to Output Shutdown Time vs. EN Voltage

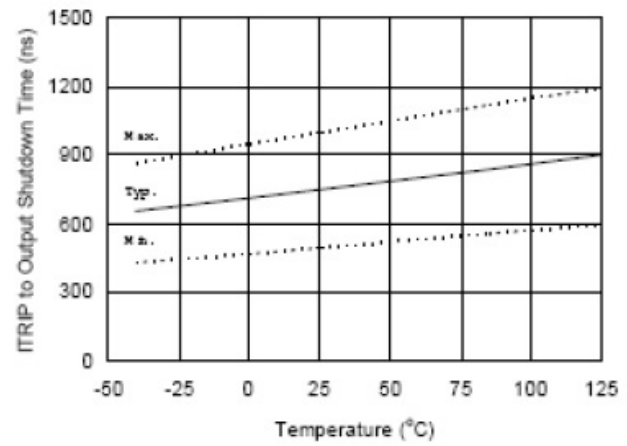


Figure 11A. ITRIP to Output Shutdown Time vs. Temperature

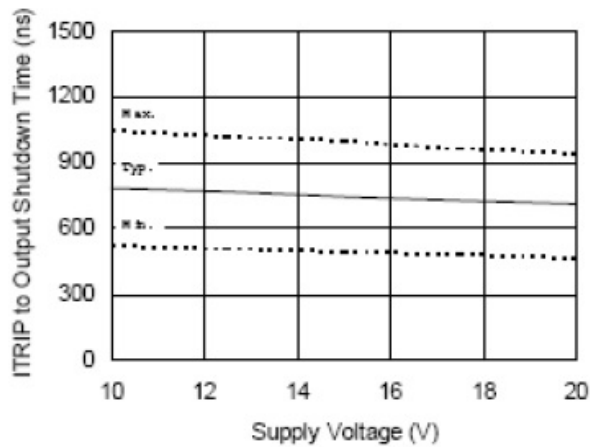


Figure 11B. ITRIP to Output Shutdown Time vs. Supply Voltage

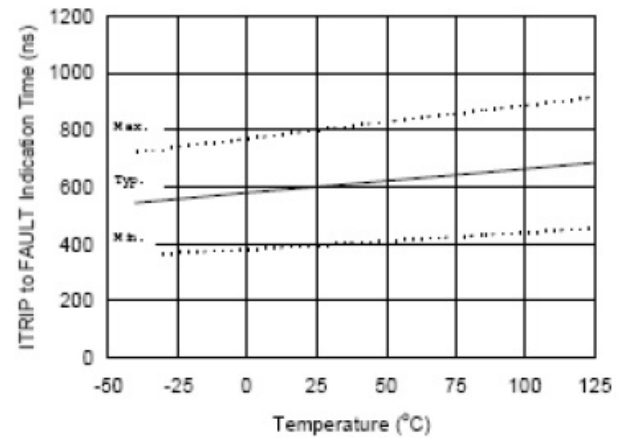


Figure 12A. ITRIP to FAULT Indication Time vs. Temperature

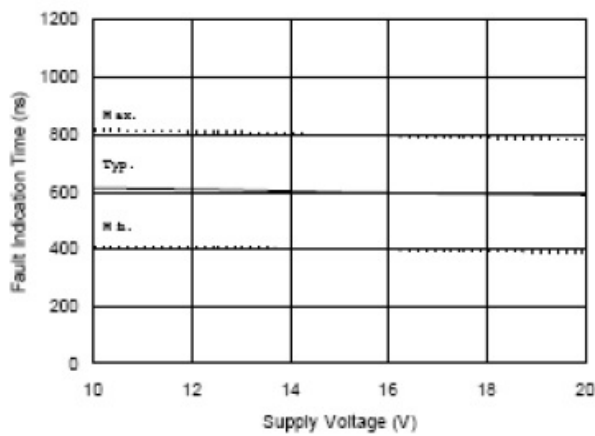


Figure 12B. ITRIP to FAULT Indication Time vs. Supply Voltage

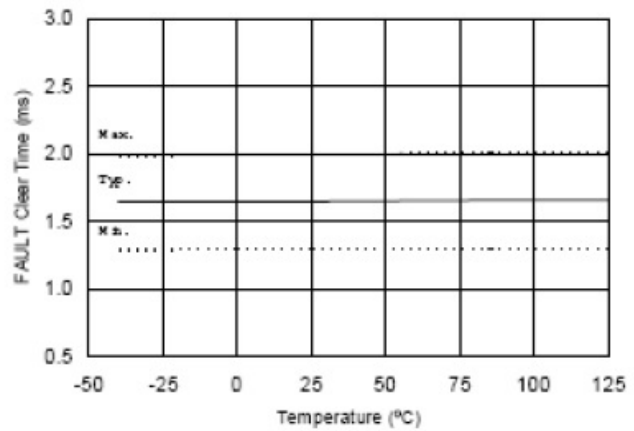


Fig13A. FAULT Clear Time vs. Temperature

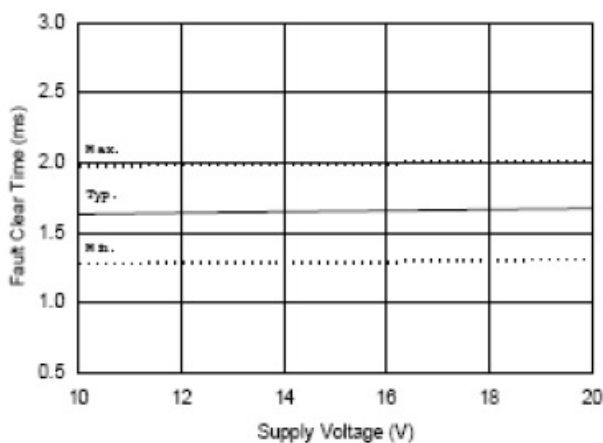


Figure 13B. FAULT Clear Time vs. Supply Voltage

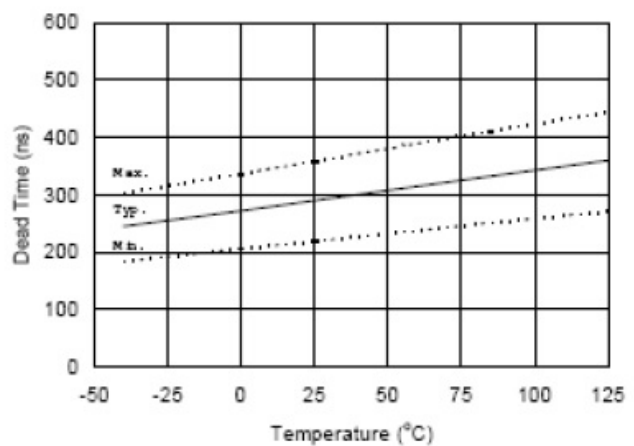


Figure 14A. Dead Time vs. Temperature

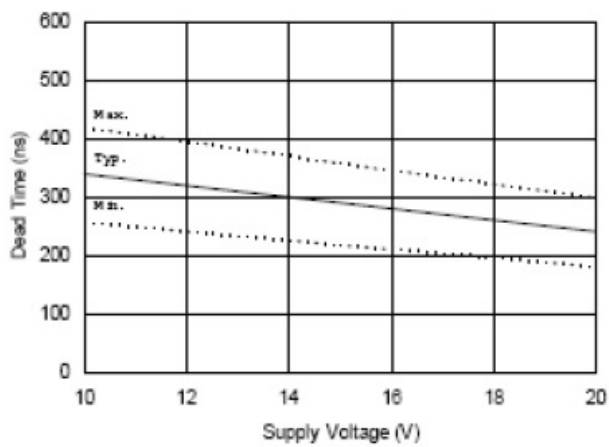


Figure 14B. Dead Time Time vs. Supply Voltage

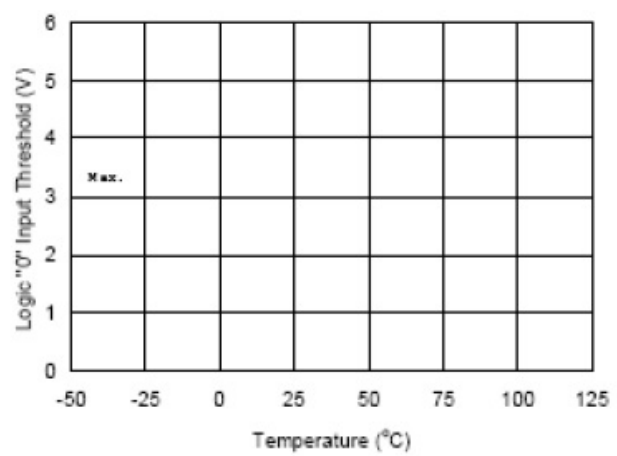


Figure 15A. Logic "0" Input Threshold vs. Temperature

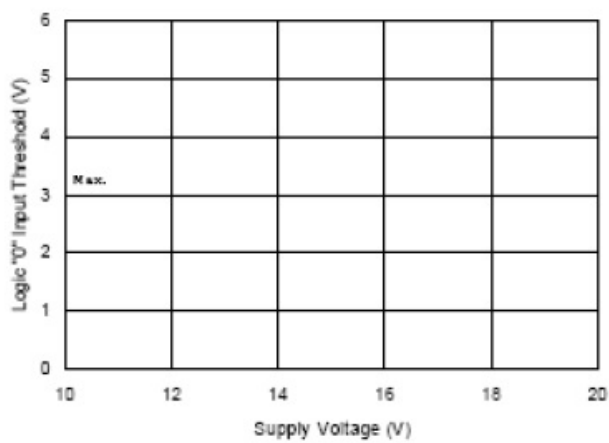


Figure 15B. Logic "0" Input Threshold vs. Supply Voltage

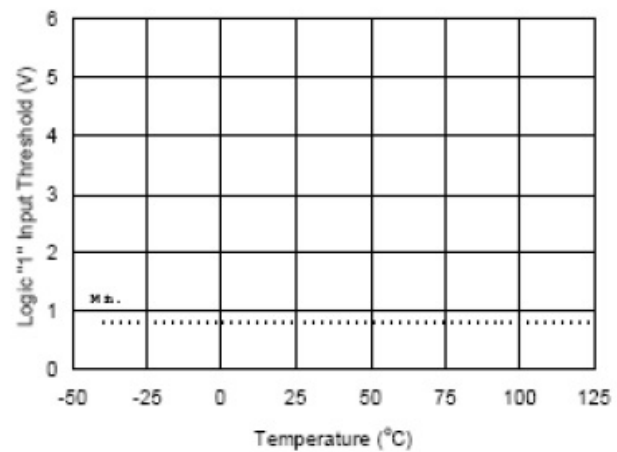


Figure 16A. Logic "1" Input Threshold vs. Temperature

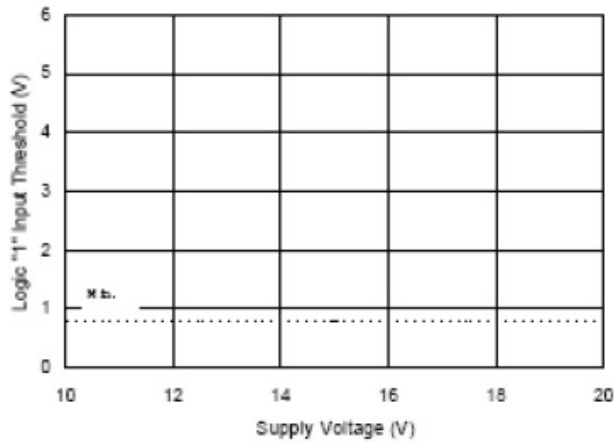


Figure 16B. Logic "1" Input Threshold vs. Supply Voltage

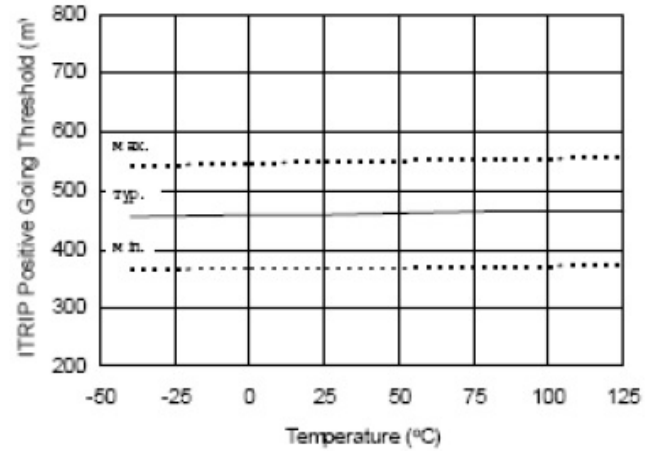


Figure 17A. ITRIP Positive Going Threshold vs. Temperature

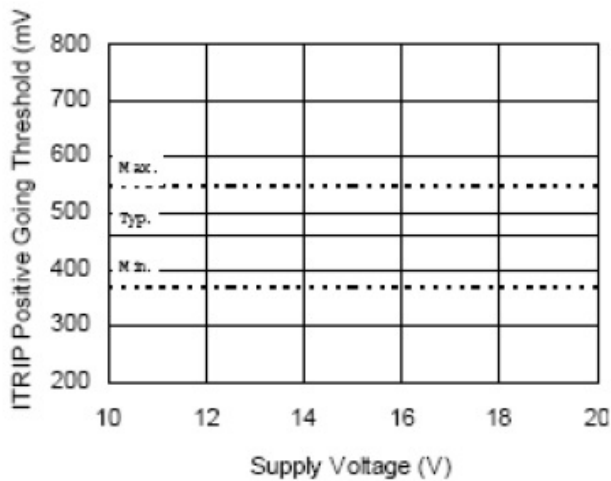


Figure 17B. ITRIP Positive Going Threshold vs. Supply Voltage

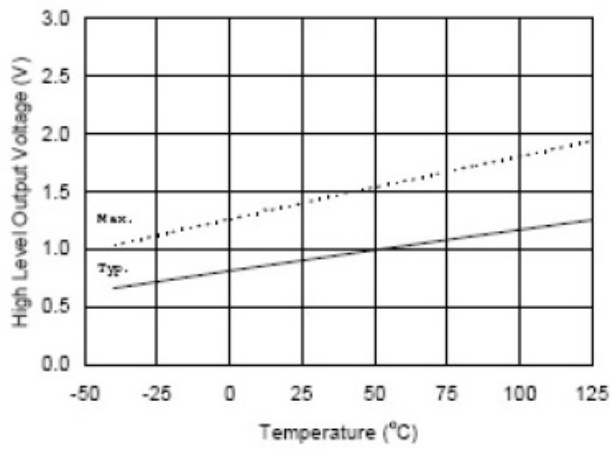


Figure 18A. High Level Output vs. Temperature

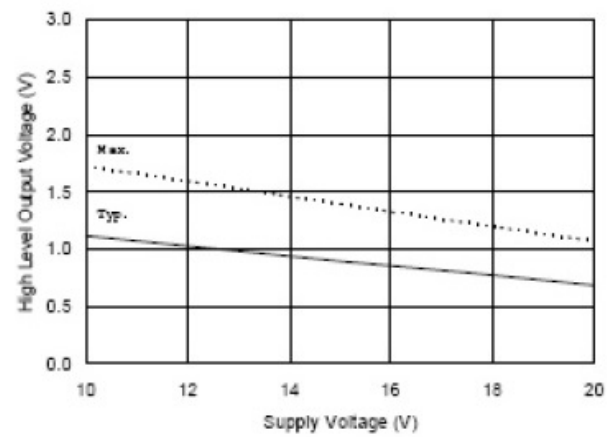


Figure 18B. High Level Output vs. Supply Voltage

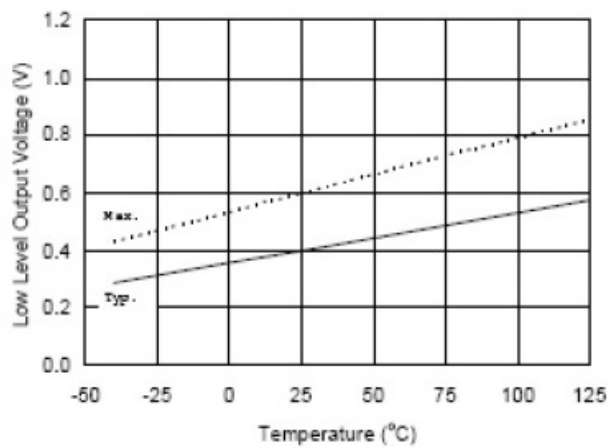


Figure 19A. Low Level Output vs. Temperature

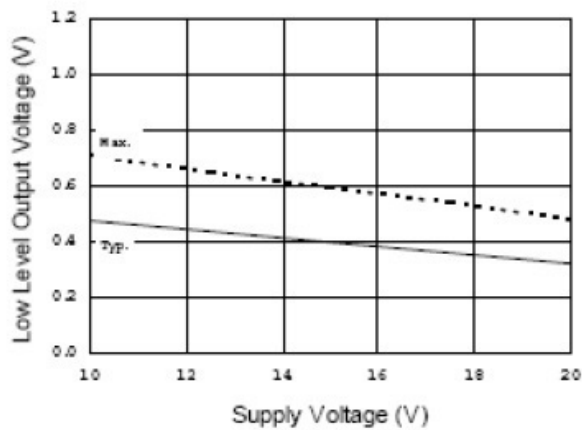


Figure 19B. Low Level Output vs. Supply Voltage

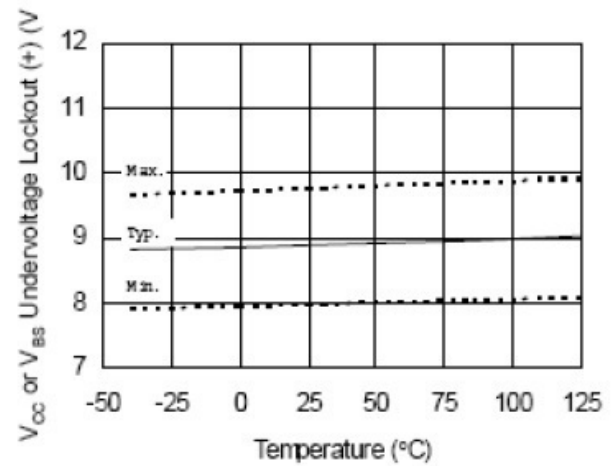


Figure 20. V_{CC} or V_{SS} Undervoltage Lockout (+) vs. Temperature

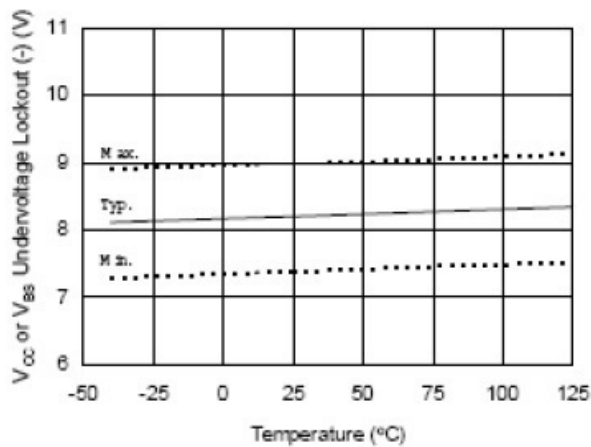


Figure 21. V_{CC} or V_{SS} Undervoltage Lockout (-) vs. Temperature

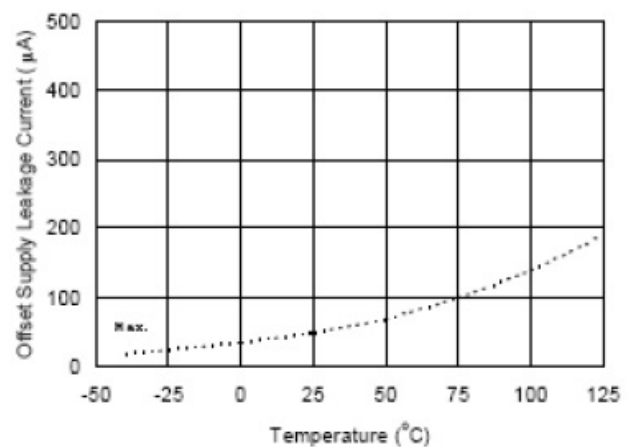


Figure 22. Offset Supply Leakage Current vs. Temperature

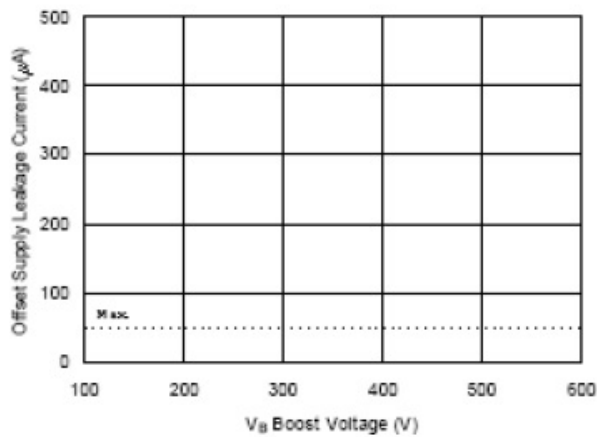


Figure 23. Offset Supply Leakage Current vs. V_B Boost Voltage

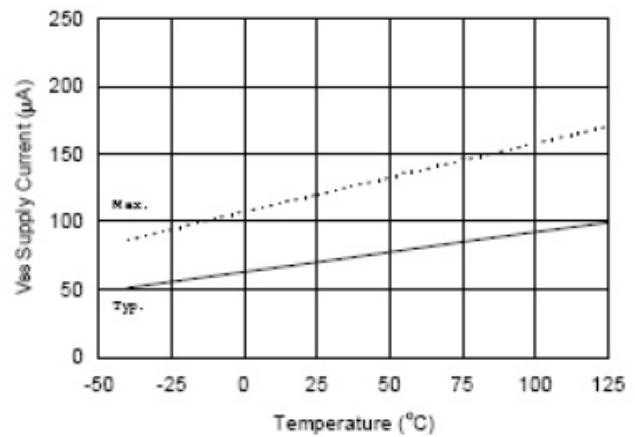


Figure 24. V_{Bs} Supply Current vs. Temperature

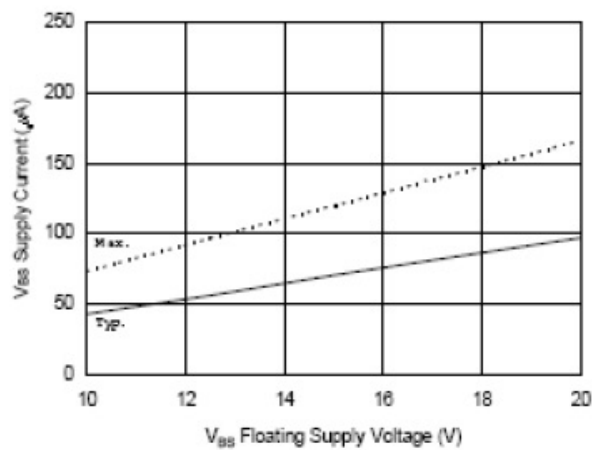


Figure 25. V_{Bs} Supply Current vs. V_{Bs} Floating Supply Voltage

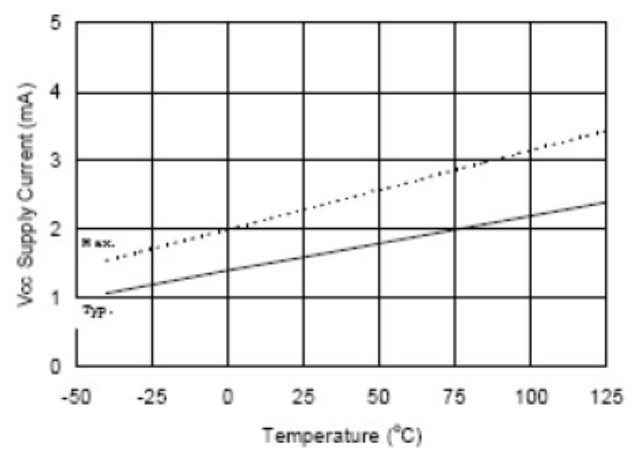


Figure 26. V_{Oc} Supply Current vs. Temperature

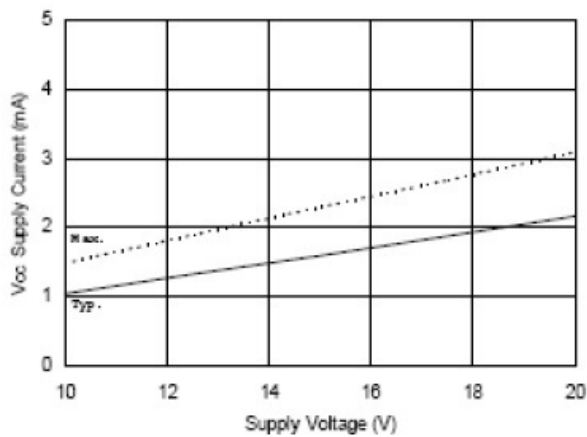


Figure 27. V_{CC} Supply Current vs. V_{CC} Supply Voltage

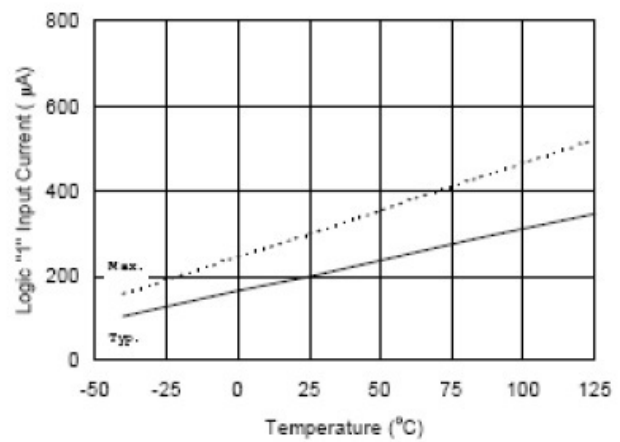


Figure 28. Logic "1" Input Current vs. Temperature

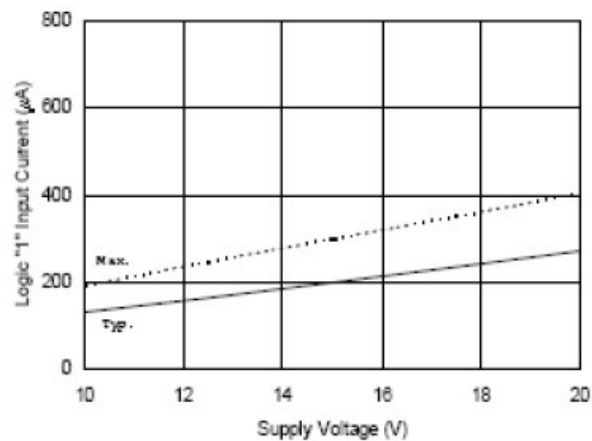


Figure 29. Logic "1" Input Current vs. Supply Voltage

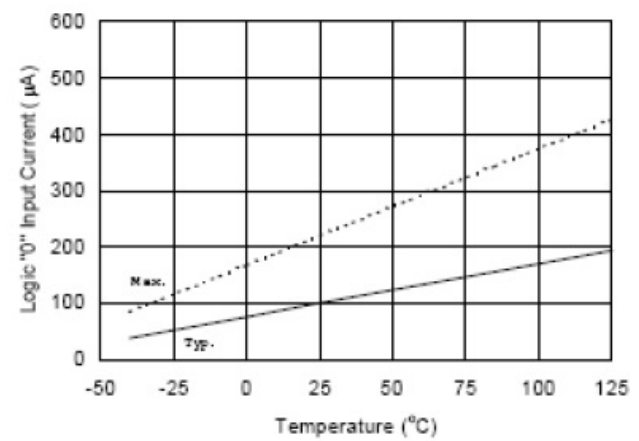


Figure 30A. Logic "0" Input Current vs. Temperature

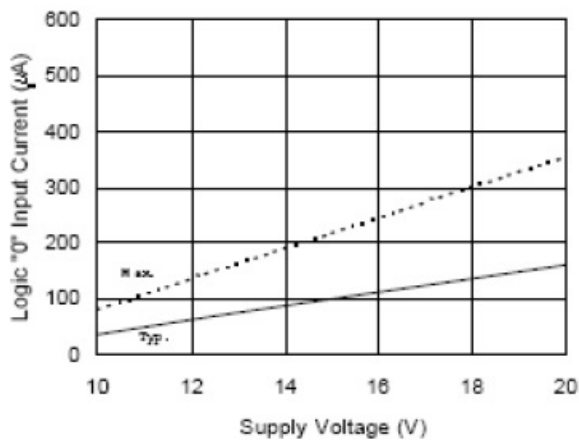


Figure 30B. Logic "0" Input Current vs. Supply

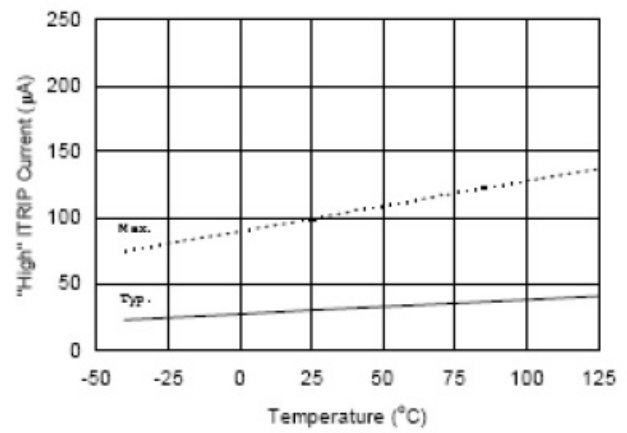


Figure 31A. "High" ITRIP Current vs. Temperature

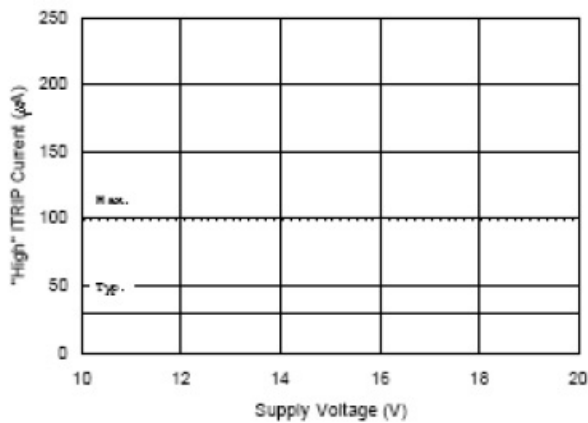


Figure 31B. "High" ITRIP Current vs. Supply Voltage

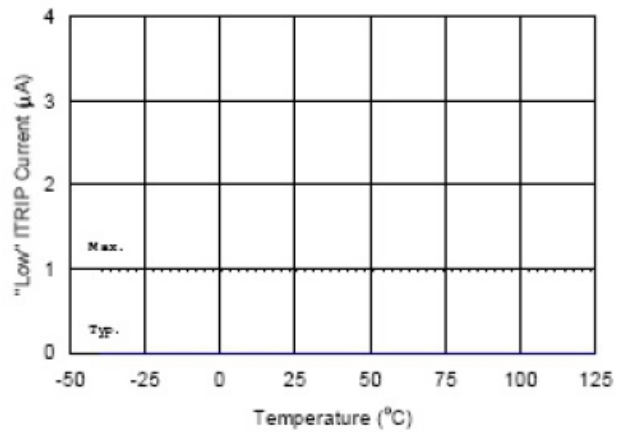


Figure 32A. "Low" ITRIP Current vs. Temperature

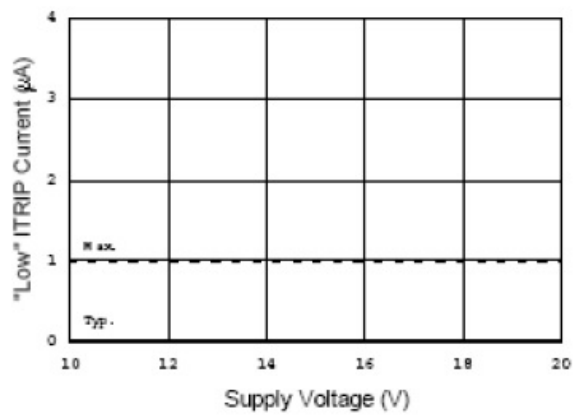


Figure 32B. "Low" ITRIP Current vs. Supply Voltage

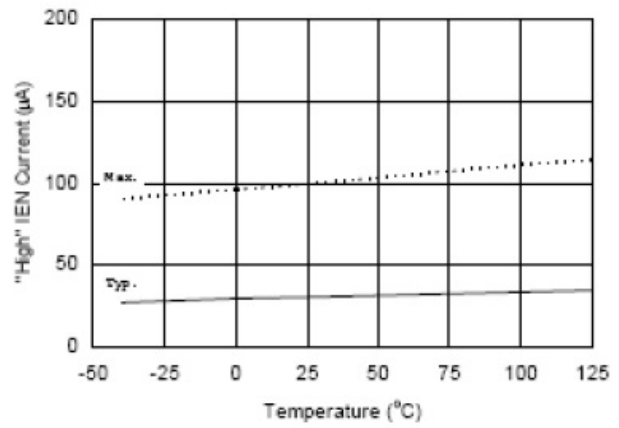


Figure 33A. "High" IEN Current vs. Temperature

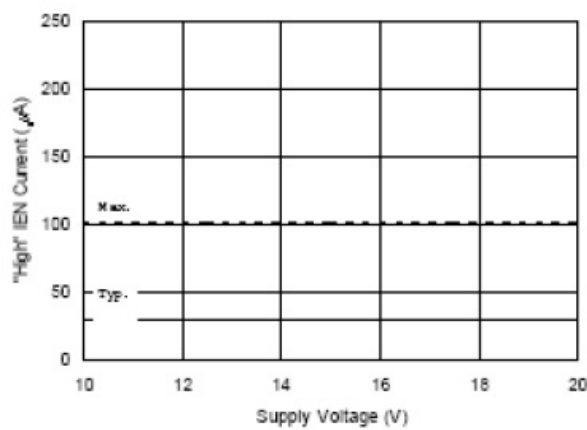


Figure 33B. "High" IEN Current vs. Supply Voltage

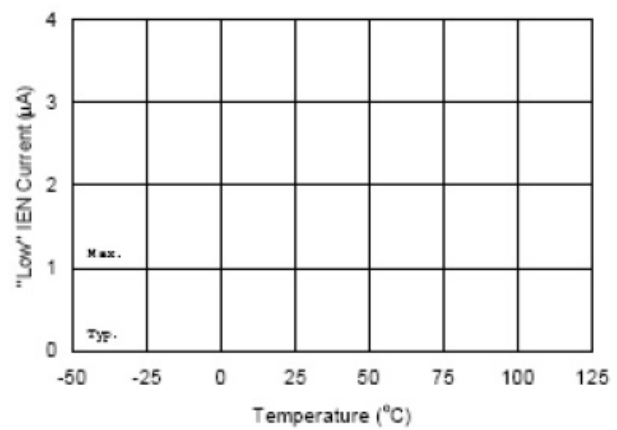


Figure 34A. "Low" IEN Current vs. Temperature

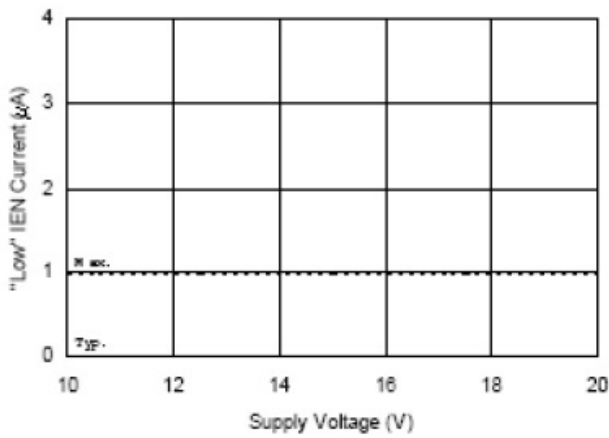


Figure 34B. "Low" IEN Current vs. Supply Voltage

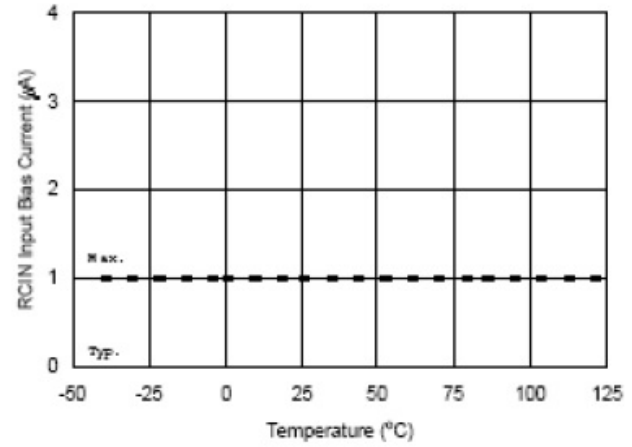


Figure 35A. RCIN Input Bias Current vs. Temperature

Figure 34B. "Low" IEN Current vs. Supply Voltage

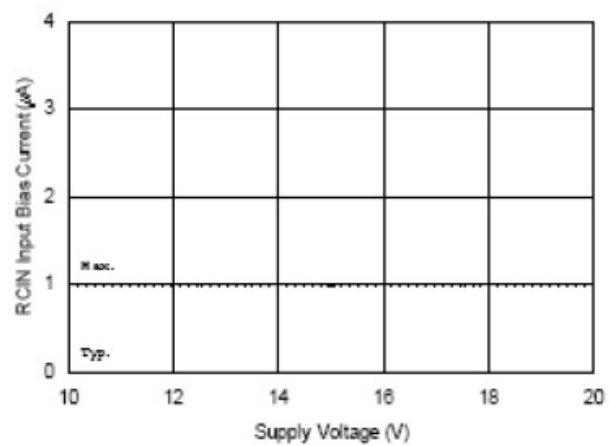


Figure 35B. RCIN Input Bias Current vs. Supply Voltage

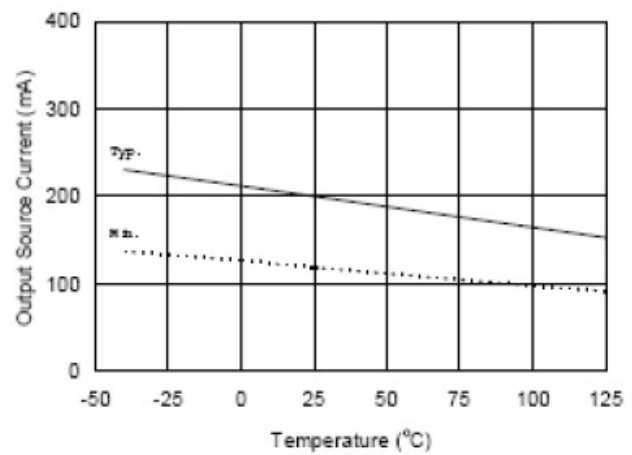


Figure 36A. Output Source Current vs. Temperature

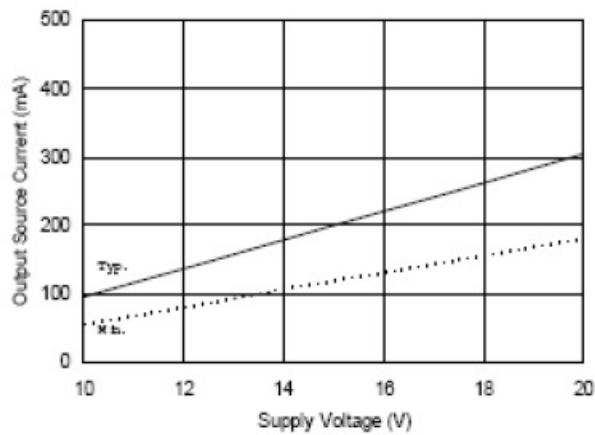


Figure 36B. Output Source Current vs. Supply Voltage

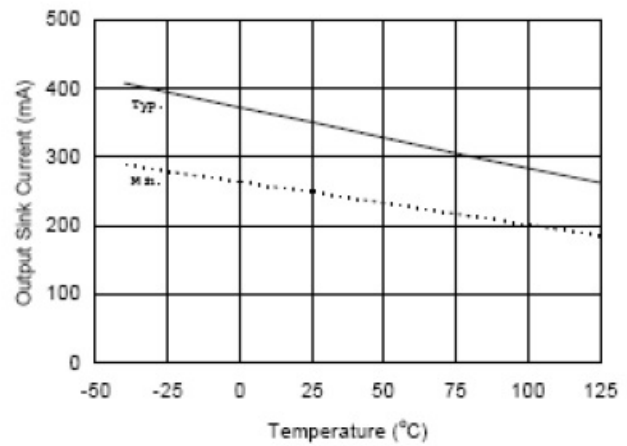


Figure 37A. Output Sink Current vs. Temperature

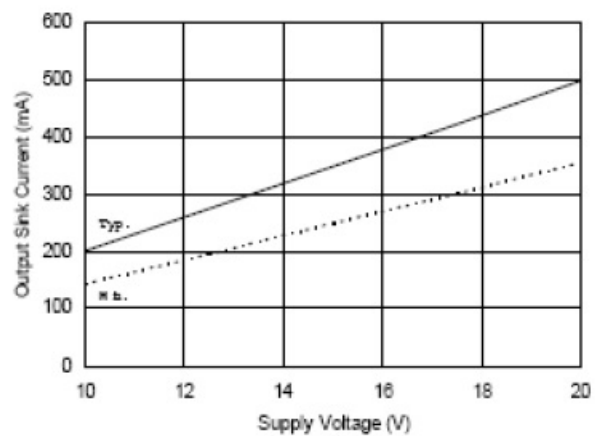


Figure 37B. Output Sink Current vs. Supply Voltage

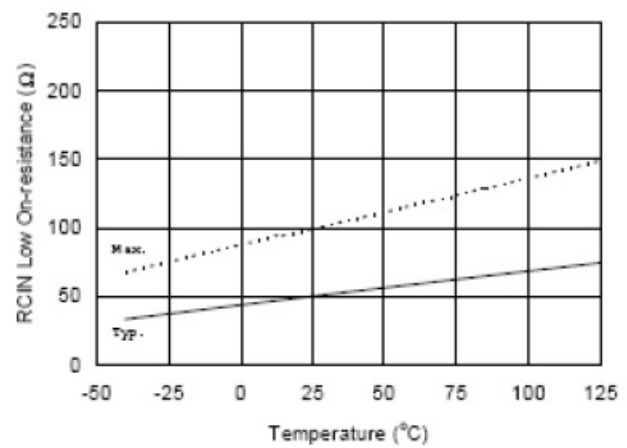


Figure 38A. RCIN Low On-resistance vs. Temperature

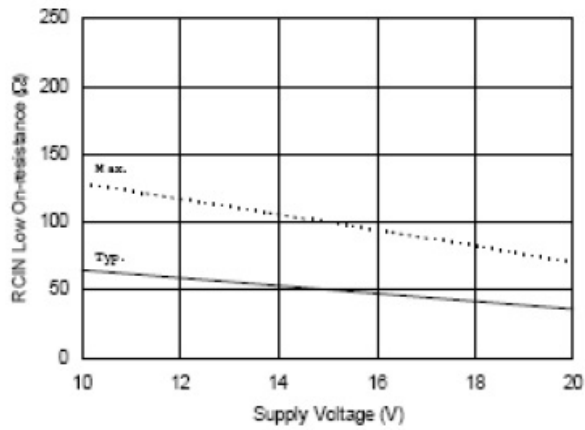


Figure 38B. RCIN Low On-resistance vs. Supply Voltage

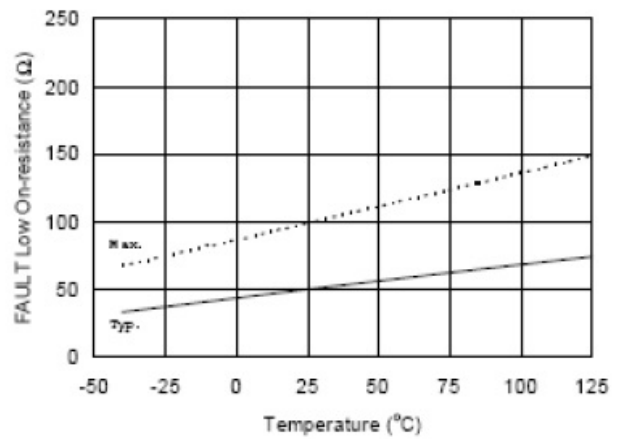


Figure 39A. FAULT Low On-resistance vs. Temperature

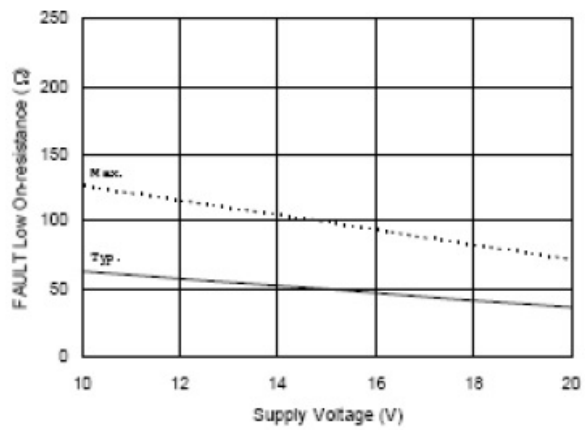


Figure 39B. FAULT Low On-resistance vs. Supply Voltage

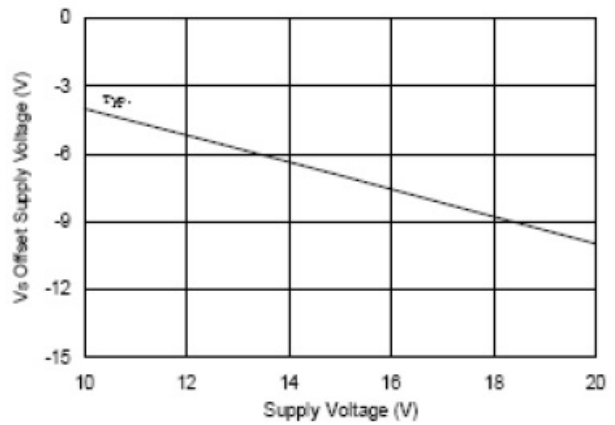
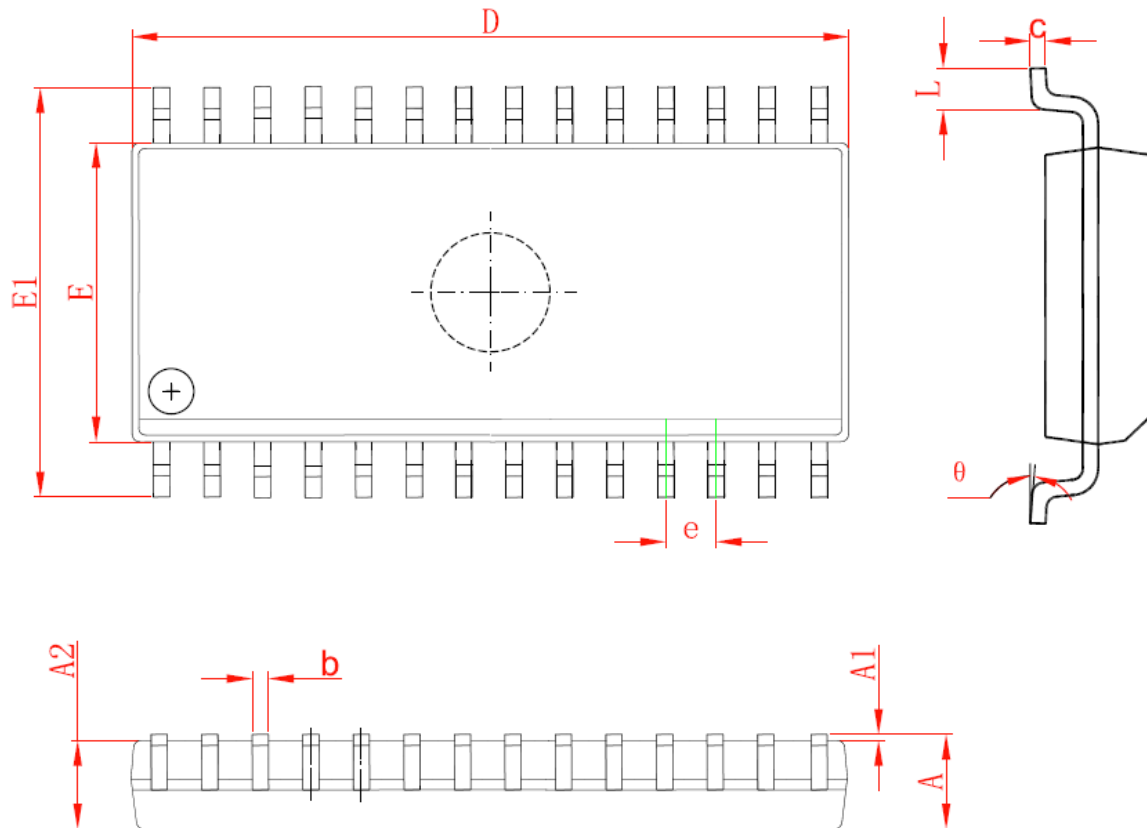


Figure 40. Maximum V_S Negative Offset vs. V_{BS} Supply Voltage

SOP28 PACKAGE OUTLINE DIMENSIONS


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	2.350	2.650	0.093	0.104
A1	0.100	0.300	0.004	0.012
A2	2.290	2.500	0.09	0.098
b	0.330	0.510	0.013	0.020
c	0.204	0.330	0.008	0.013
D	17.700	18.100	0.697	0.713
E	7.400	7.700	0.291	0.303
E1	10.210	10.610	0.402	0.418
e	1.270 (BSC)		0.050 (BSC)	
L	0.400	1.270	0.016	0.050
θ	0°	8°	0°	8°

Revision History

Note: page numbers for previous revisions may differ from page numbers in current version

Page or Item	Subjects (major changes since previous revision)
Rev 1.0 datasheet, 2019-8-27	
Whole document	New company logo released
Page 1	Remove "Figure1" and "June 2019"
Page 6	Revise $V_{RCIN,HYS}$ parameter
Rev 1.0 datasheet, 2019-11-27	
Page 1	Remove a typo
Page 2	Change order information